

# Supporting information

## **8.0% Efficient Sub-Micron CuIn(S,Se)<sub>2</sub> Solar Cells on Sn:In<sub>2</sub>O<sub>3</sub>**

### **Back Contact via a Facile Solution Process**

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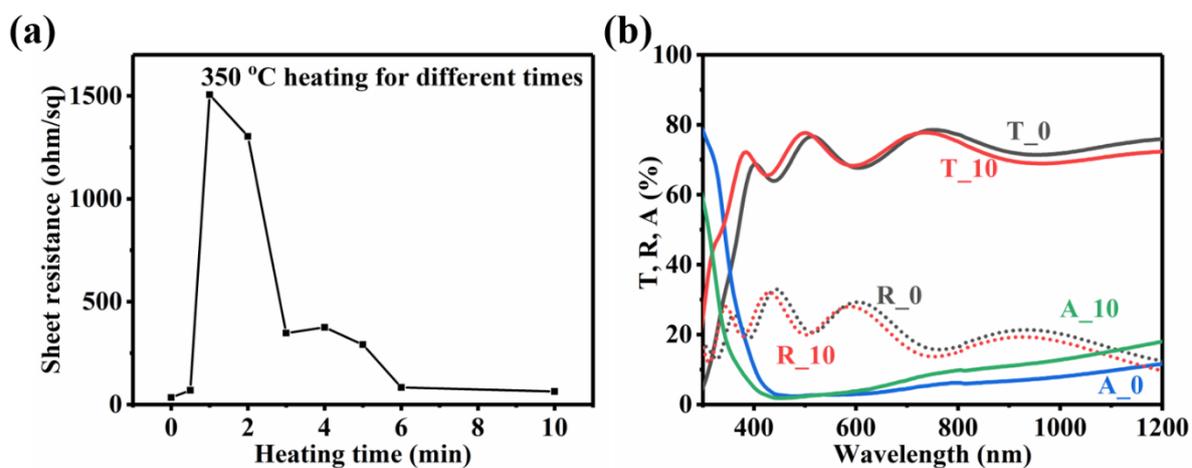


Figure S1 (a) Sheet resistance of 400 nm ITO films heated for different times at 350 °C under atmospheric conditions; (b) transmission, reflection, and absorption properties of 400 nm ITO without heating (T<sub>0</sub>, R<sub>0</sub>, and A<sub>0</sub>) and with 10 min heating (T<sub>10</sub>, R<sub>10</sub>, and A<sub>10</sub>).

Table S1 Composition of ultra-thin absorbers obtained under different selenization temperatures measured by XRF.

	Cu (at%)	In (at%)	Se (at%)	S (at%)	Cu/In	S/(S+Se)
500 °C	21.63	28.52	47.36	2.12	0.76	0.04
520 °C	19.50	25.32	35.23	19.62	0.77	0.36
540 °C	20.60	26.08	39.74	13.19	0.79	0.25
560 °C	18.04	23.83	25.86	31.92	0.76	0.55

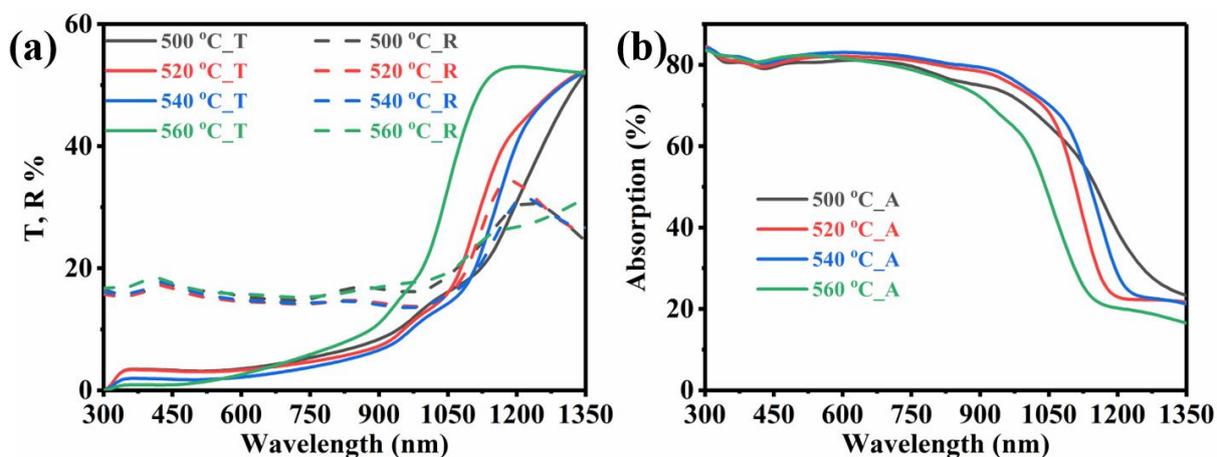


Figure S2 (a) transmission (solid line) and reflection (dashed line), (b) absorption of CISSe absorbers deposited on soda lime glass with various selenization temperatures.

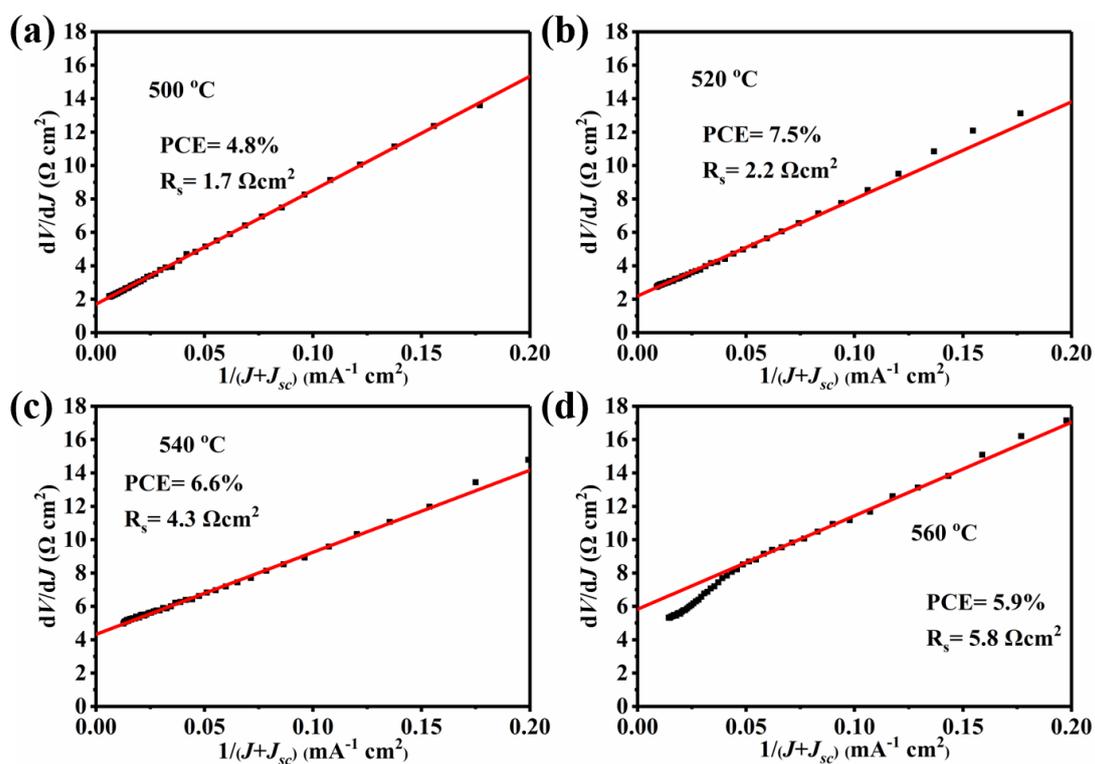


Figure S3 Determination of series resistance ( $R_s$ ) for ultra-thin absorbers deposited on ITO back contact and selenized at different temperatures.

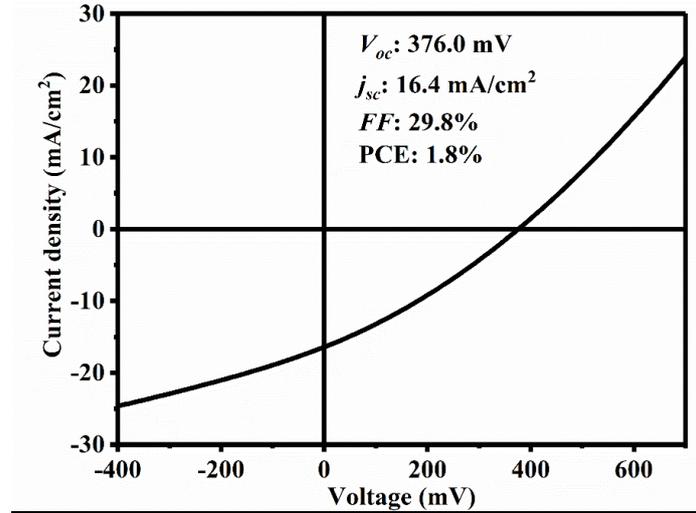


Figure S4  $J$ - $V$  curve of CISSe device with micron absorber thickness (1440 nm).

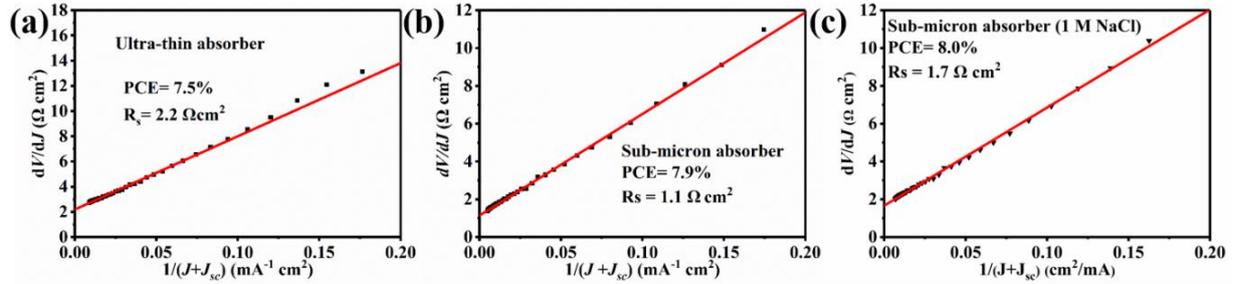


Figure S5 Determination of series resistance ( $R_s$ ) for (a) ultra-thin absorber, (b) sub-micron absorber, and (c) sub-micron absorber with NaCl treatment deposited on ITO back contact and selenized at 520 °C.

Table S2 Averaged (over six devices) and best CISSe photovoltaic device parameters without and with various concentrations of NaCl treatment. The absorber thickness is 740 nm.

	$V_{oc}$ (mV)	$j_{sc}$ (mA/cm <sup>2</sup> )	$FF$ (%)	$\eta$ (%)
no additional NaCl	448.5±2.6	29.1±0.6	56.3±3.2	7.3±0.4
	445.6	29.7	59.8	7.9
0.4 M NaCl	449.3±3.9	29.2±0.6	57.2±1.3	7.5±0.1
	450.0	29.2	58.8	7.7
0.8 M NaCl	432.6±9.9	28.3±1.2	53.4±3.3	6.5±0.6
	439.9	27.6	59.0	7.2
1 M NaCl	463.9±5.9	28.2±0.6	58.0±2.0	7.6±0.3
	466.0	28.7	59.6	8.0

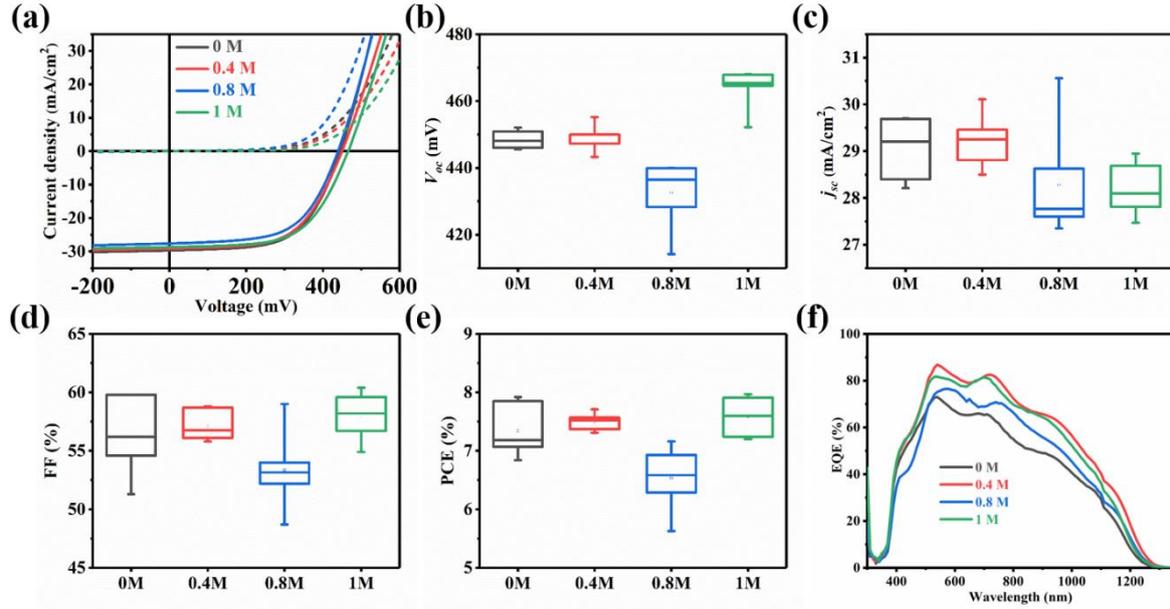


Figure S6 (a)  $J$ - $V$  curves and (f) EQE spectra of the best sub-micron CISSe devices without and with different concentrations of NaCl for preselenization treatment. The distribution of (b)  $V_{oc}$ , (c)  $j_{sc}$ , (d)  $FF$ , and (e) PCE.

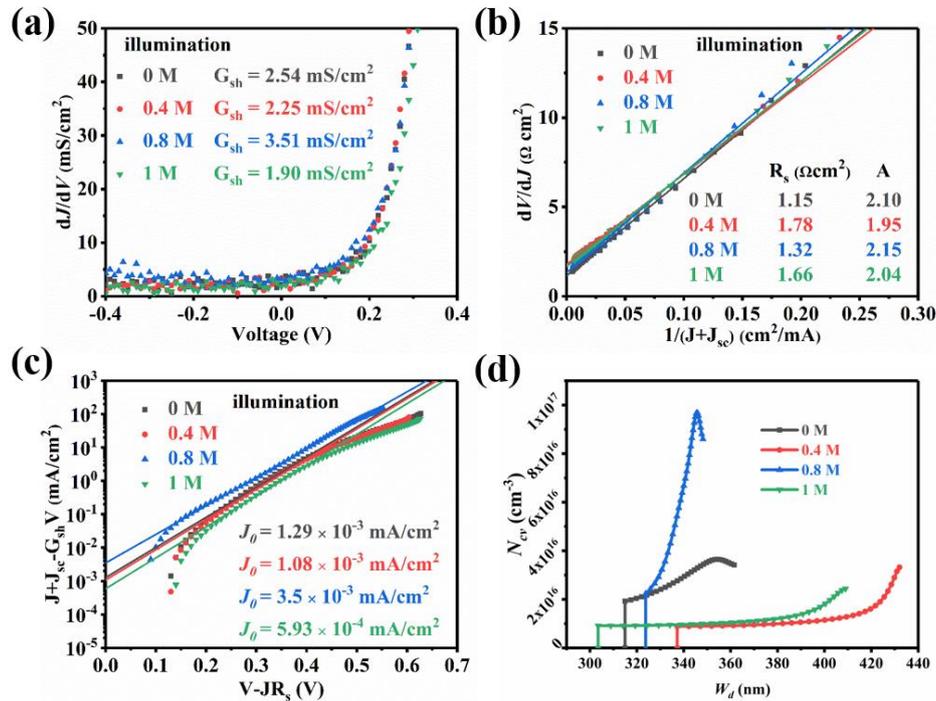


Figure S7 Plots of (a)  $dJ/dV$  vs.  $V$  for extraction of  $G_{sh}$ , (b)  $dV/dJ$  vs.  $1/(J+J_{sc})$  for derivation of  $R_s$  and  $A$ , and (c) semi-logarithmic plot of  $J+J_{sc}-G_{sh}V$  vs.  $V-JR_s$  to determine  $J_0$ ; (d) space-charge density  $N_{cv}$  and depletion width  $W_d$  for CISSe solar cells with sub-micron absorber without NaCl and with various concentrations of NaCl for preselenization treatment.

Table S3 Summary of electrical parameters extracted from further  $J$ - $V$  and  $C$ - $V$  analysis of the best CISSe solar cells without and with various concentrations of NaCl treatment. The absorber thickness was 740 nm.

	$G_{sh}$ (mS/cm <sup>2</sup> )	$R_{sh}$ ( $\Omega \cdot \text{cm}^2$ )	$R_s$ ( $\Omega \cdot \text{cm}^2$ )	$j_0$ (mA/cm <sup>2</sup> )	A	$N_{cv}$ (cm <sup>-3</sup> )	$W_d$ (nm)
no additional NaCl	2.54	393.70	1.15	$1.29 \times 10^{-3}$	2.10	$1.9 \times 10^{16}$	315.0
0.4 M NaCl	2.25	444.44	1.78	$1.08 \times 10^{-3}$	1.95	$8.9 \times 10^{15}$	337.3
0.8 M NaCl	3.51	284.90	1.32	$3.50 \times 10^{-3}$	2.15	$2.2 \times 10^{16}$	323.8
1 M NaCl	1.90	526.32	1.66	$5.93 \times 10^{-4}$	2.04	$9.1 \times 10^{15}$	303.5

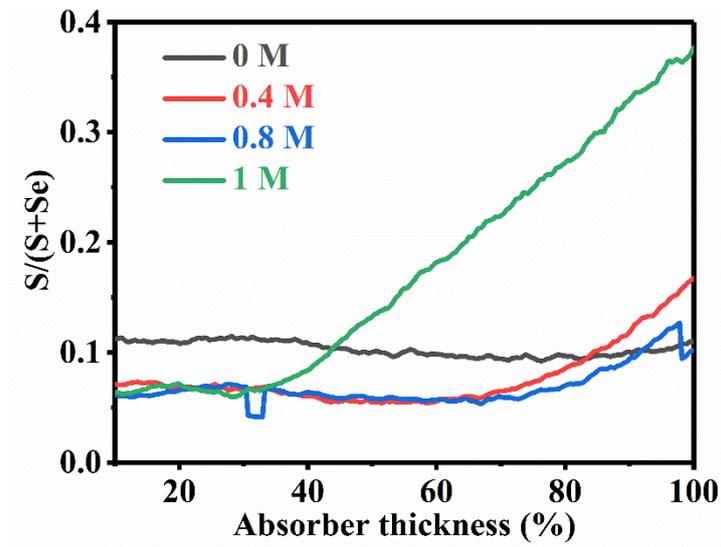


Figure S8  $S/(S+Se)$  ratios of sub-micron absorbers subject to different concentrations of NaCl solution for preselenization treatment.

Table S4 Overview on high-performance CIGSSe-based solar cells deposited on transparent conductive back contact via a solution process.

Precursor	Deposition	Device	Thickness	$\eta$	Reference
Cu and In oxide NPs and Ga oxide	Screen printing	FTO/Cu(In,Ga)Se <sub>2</sub> /CdS/i-ZnO/ZnO:Al	1.3 $\mu\text{m}$	6.1%	[S1]
CuIn <sub>x</sub> Ga <sub>1-x</sub> S <sub>2</sub> nanoparticles	doctor blading	FTO/Cu(In,Ga)Se <sub>2</sub> /CdS/i-ZnO/ZnO:Al	2 $\mu\text{m}$	6.5%	[S2]
Cu(NO <sub>3</sub> ) <sub>2</sub> , In(NO <sub>3</sub> ) <sub>3</sub> and Ga(NO <sub>3</sub> ) <sub>3</sub>	spin-coating	ITO/Cu(In,Ga)S <sub>2</sub> /CdS/i-ZnO/ZnO:Al	800 nm	5.7%	[S3]
			1.1 $\mu\text{m}$	6.6%	[S4]
CuCl, InCl <sub>3</sub> and Thiourea	spin-coating	ITO/CuIn(S,Se) <sub>2</sub> /CdS/i-ZnO/ZnO:Al	550 nm	7.5%	Our work
			740 nm	8.0%	

## References

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